

Laser Module Burn In System

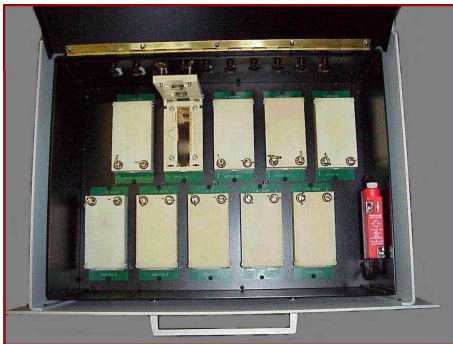
Product Information

Test Evolutions Ltd's laser module burn in systems have been developed to provide a highly versatile test platform for either burn in or endurance testing requirements. The system is based on an number of independent trays mounted in a cabinet and controlled by a PC mounted in the cabinet. Additional trays can be added to the system at any time or for larger systems additional racks can be added, all controlled by the same program. An integral LCD monitor is provided for control of the burn in test and data display.

Each tray contains the drive / monitor electronics and device fixtures for up to 12 lasers. Many drive / monitor circuits already exist for several laser device types such as standard lasers, tunable lasers, transmitters and SOA's. These designs can be easily modified to suit a specific device or specification requirement.

The device test fixtures are removable allowing the system to be configured for several different package styles or changed to a totally different device at a later date extending the life of the equipment and reducing modification costs. Test fixtures can be developed to specific customer requirements with several designs already available. Case temperature can be controlled either by heater or TEC devices depending on performance and budget requirements.

To enable full flexibility with the system hardware our software also has to be versatile. The user can define burn in parameters on a per tray or per device basis. Pushed to its limit the user can invoke a different burn in test, with a different set of drive conditions and different laser packages in each tray. The system can also be configured to automatically conduct periodic LIV sweeps on devices while on test (depending on hardware configuration). Analysis of the LIV data (I.e. threshold, slope efficiency, etc) can also be enabled. Again this functionality can be set on a per tray basis.



The data obtained is displayed on the integral LCD screen and logged to file within the system. Burn in data can be logged down to 1 minute intervals for every device in the system. LIV sweeps can be typically taken at down to 1 hour intervals for every device (dependent on system size). The software has a automatic test recovery function so if the test is interrupted for any reason (I.e. power fail) it will be automatically restarted and continue from the point it was interrupted.

These systems have proved to be so versatile that they can be not only as burn in systems but also as life test systems and for engineering as tool for device development

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